

4 element SDD system

MADE IN JAPAN

SYSTEM

High-Count rate / High-Sensitivity by multi-element SDD with appropriated DSP

This system realize high-sensitivity by multiple SDD with high-count rate and high-energy resolution. It is possible by Transistor Reset Processing and Digital Signal Processing.

XSDD50-04

10⁻⁵ Pa
Corresponding
Vacuum



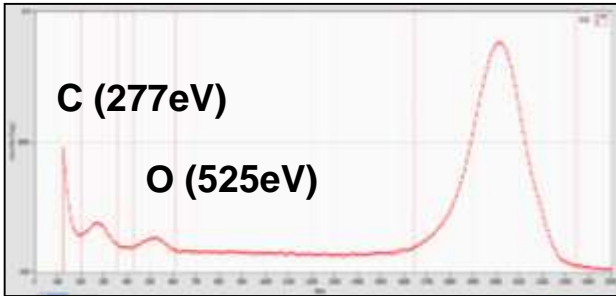
Customizable
Flange type / Cylinder size

Recommended
Measurement Module
APN504XGbE

High Speed ADC
(100Msps, 14-bit)
&
Highly Integrated FPGA

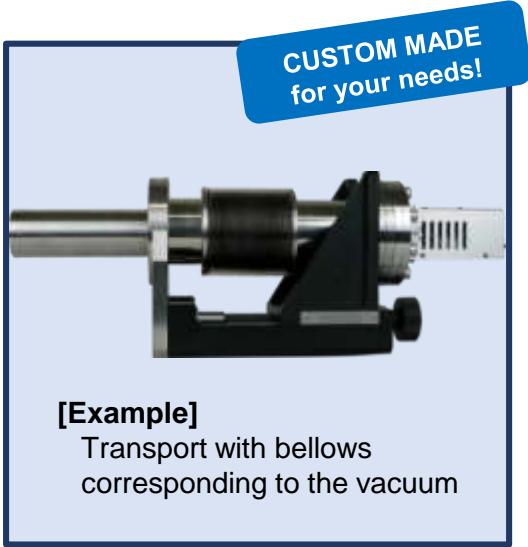


Selectable
• Active Area: 30mm² / 50mm²
• Window: Be / AP3.3 / Window-less



[Example]
Spectrum of soft X-rays

Detector	Silicon Drift Detector 50mm ² , Window-less / AP3.3 / Be
Element area	260mm ² (65mm ² × 4 element)
Active area	200mm ² (65mm ² collimated to 50mm ² × 4 element)
Measurement mode	Histogram, List, Waveform, ROI-SCA
ADC	4CH 100Msps 14-bit
Energy resolution (typ.)	244eV@5.9keV MnKα *Peaking time: 0.25μs, 1000kOCR
SDD power supply	-200 V, ±5V, +3.3V
Throughput	Max. 150kcps: 2us Max. 1000kcps: 0.15us
Interface	Ethernet (TCP/IP)
Option	Z-axis movement mechanism, UHV valve
Vacuum capable	<10 ⁻⁵ Pa
Flange type	ICF114 (Standard)
Accessory	Software, Instruction Manual



[Example]
Transport with bellows
corresponding to the vacuum

*Images is for illustration purpose.
*Please note that contents may change without prior notice.

TechnoAP

Design and fabrication of electronic circuit associated with measurement control and radiation measurement

TechnoAP Co., Ltd.

+81-29-350-8011
+81-29-352-9013
2976-15 Mawatari, Hitachinaka-shi, Ibaraki, 312-0012, Japan
<http://www.techno-ap.com>
order@techno-ap.com

Updated on 2017/10/17